

# F1-2 PACK SIC MOSFET Module

## Product Preview

# NXH010P90MNF1PTG, NXH010P90MNF1PG

The NXH010P120MNF1 is a power module containing an  $10\,\text{m}\Omega/900$  V SiC MOSFET half bridge and a thermistor in an F1 package.

#### **Features**

- 10 mΩ/900 V SiC MOSFET Half Bridge
- Thermistor
- Options with Pre-applied Thermal Interface Material (TIM) and without Pre-applied TIM
- Press-fit Pins

## **Typical Applications**

- Solar Inverter
- Uninterruptible Power Supplies
- Electric Vehicle Charging Stations
- Industrial Power

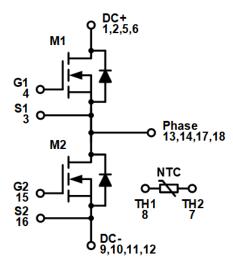
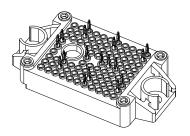


Figure 1. NXH010P90MNF1 Schematic Diagram

This document contains information on a product under development. **onsemi** reserves the right to change or discontinue this product without notice.



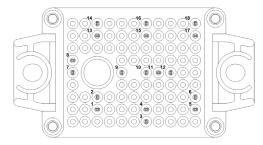
PIM18 33.8x42.5 (PRESS FIT) CASE 180BW

#### **MARKING DIAGRAM**



NXH010P90MNF1PTG = Specific Device Code
NXH010P90MNF1PG = Specific Device Code
AT = Assembly & Test Site Code
YYWW = Year and Work Week Code

## **PIN CONNECTIONS**



See Pin Function Description for pin names

## **ORDERING INFORMATION**

See detailed ordering and shipping information on page 4 of this data sheet.

## **PIN FUNCTION DESCRIPTION**

Pin	Name	Description
1	DC+	DC Positive Bus connection
2	DC+	DC Positive Bus connection
3	S1	Q1 Kelvin Emitter (High side switch)
4	G1	Q1 Gate (High side switch)
5	DC+	DC Positive Bus connection
6	DC+	DC Positive Bus connection
7	TH2	Thermistor Connection 2
8	TH1	Thermistor Connection 1
9	DC-	DC Negative Bus connection
10	DC-	DC Negative Bus connection
11	DC-	DC Negative Bus connection
12	DC-	DC Negative Bus connection
13	PHASE	Center point of half bridge
14	PHASE	Center point of half bridge
15	G2	Q2 Gate (Low side switch)
16	S2	Q2 Kelvin Emitter (High side switch)
17	PHASE	Center point of half bridge
18	PHASE	Center point of half bridge

## **MAXIMUM RATINGS**

Rating	Symbol	Value	Unit
SIC MOSFET			
Drain-Source Voltage	V <sub>DSS</sub>	900	V
Gate-Source Voltage	V <sub>GS</sub>	+18/-8	V
Continuous Drain Current @ T <sub>C</sub> = 80°C (T <sub>J</sub> = 175°C)	I <sub>D</sub>	154	Α
Pulsed Drain Current (T <sub>J</sub> = 175°C)	I <sub>Dpulse</sub>	308	Α
Maximum Power Dissipation (T <sub>J</sub> = 175°C)	P <sub>tot</sub>	328	W
Minimum Operating Junction Temperature	T <sub>JMIN</sub>	-40	°C
Maximum Operating Junction Temperature	$T_{JMAX}$	175	°C
THERMAL PROPERTIES			
Storage Temperature range	T <sub>stg</sub>	-40 to 150	°C
INSULATION PROPERTIES			
Isolation test voltage, t = 1 s, 60 Hz	V <sub>is</sub>	4800	V <sub>RMS</sub>
Creepage distance		12.7	mm

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### **RECOMMENDED OPERATING RANGES**

Rating	Symbol	Min	Max	Unit
Module Operating Junction Temperature	TJ	-40	150	°C

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

<sup>1.</sup> Refer to ELECTRICAL CHĂRACTERISTICS, RECOMMENDED OPERATING RANGES and/or APPLICATION INFORMATION for Safe Operating parameters.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Test Conditions Symbol		Min	Тур	Max	Unit
SIC MOSFET CHARACTERISTICS						
Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 400 \mu\text{A}$	$V_{(BR)DSS}$	900	-	-	V
Zero Gate Voltage Drain Current	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 900 V	I <sub>DSS</sub>	=	=	200	μА
Drain-Source On Resistance	V <sub>GS</sub> = 15 V, I <sub>D</sub> = 100 A, T <sub>J</sub> = 25°C	R <sub>DS(ON)</sub>	=	10.03	14	mΩ
	V <sub>GS</sub> = 15 V, I <sub>D</sub> = 100 A, T <sub>J</sub> = 125°C		=	10.08	=	
	V <sub>GS</sub> = 15 V, I <sub>D</sub> = 100 A, T <sub>J</sub> = 150°C	] [	-	11.61	-	
Gate-Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 40 \text{ mA}$	V <sub>GS(TH)</sub>	1.8	2.74	4.3	V
Gate Leakage Current	$V_{GS} = -5/15 \text{ V}, V_{DS} = 0 \text{ V}$	$I_{GSS}$	-500	_	500	nA
Internal Gate Resistance		$R_{G}$		0.8		Ω
Input Capacitance	$V_{DS} = 450 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	C <sub>ISS</sub>	-	7007	-	pF
Reverse Transfer Capacitance		C <sub>RSS</sub>	-	44	-	
Output Capacitance		C <sub>OSS</sub>	_	665	-	
C <sub>OSS</sub> Stored Energy	$V_{DS} = 0 \text{ V to } 800 \text{ V}, V_{GS} = 0 \text{ V}$	E <sub>OSS</sub>	_	251	-	μJ
Total Gate Charge	$V_{DS} = 720 \text{ V}, V_{GS} = -15/15 \text{ V},$	Q <sub>G(TOTAL)</sub>	=	546.4	-	nC
Gate-Source Charge	I <sub>D</sub> = 100 A	$Q_{GS}$	-	105.45	-	nC
Gate-Drain Charge		$Q_{GD}$	-	122.7	-	nC
Turn-on Delay Time	T <sub>J</sub> = 25°C	t <sub>d(on)</sub>	-	61.2	-	ns
Rise Time	$V_{DS} = 600 \text{ V}, I_{D} = 100 \text{ A}$	t <sub>r</sub>	=	16.5	=	
Turn-off Delay Time	$V_{GS} = -5 \text{ V/18 V}, R_{G} = 1.5 \Omega$	t <sub>d(off)</sub>	=	148	=	
Fall Time		t <sub>f</sub>	-	11.9	_	
Turn-on Switching Loss per Pulse		E <sub>ON</sub>	-	0.65	-	mJ
Turn off Switching Loss per Pulse		E <sub>OFF</sub>	-	1.18	-	
Turn-on Delay Time	T <sub>J</sub> = 150°C	t <sub>d(on)</sub>	_	58.4	_	ns
Rise Time	$V_{DS} = 600 \text{ V}, I_D = 100 \text{ A}$	t <sub>r</sub>	_	15.6	_	
Turn-off Delay Time	$V_{GS} = -5 \text{ V/18 V}$ , $R_G = 1.5 \Omega$	t <sub>d(off)</sub>	_	164	_	
Fall Time		t <sub>f</sub>	_	13.1	_	
Turn-on Switching Loss per Pulse		E <sub>ON</sub>	_	0.71	_	mJ
Turn off Switching Loss per Pulse		E <sub>OFF</sub>	=	1.23	=	
Diode Forward Voltage	I <sub>D</sub> = 100 A, T <sub>J</sub> = 25°C	$V_{SD}$	=	4.47	6	V
	I <sub>D</sub> = 100 A, T <sub>J</sub> = 150°C	1	-	3.92	_	
Reverse Recovery Time	T <sub>J</sub> = 25°C	t <sub>rr</sub>	_	19.4	_	ns
Reverse Recovery Charge	$V_{DS} = 600 \text{ V}, I_D = 100 \text{ A}$	Q <sub>rr</sub>	_	821	_	nC
Peak Reverse Recovery Current	$V_{GS}$ = -5 V/18 V, $R_{G}$ = 1.5 $\Omega$	I <sub>RRM</sub>	-	64.2	_	Α
Peak Rate of Fall of Recovery Current		di/dt	_	8995	_	A/μs
Reverse Recovery Energy		E <sub>rr</sub>	=	400	-	μJ
Reverse Recovery Time	T <sub>J</sub> = 150°C	t <sub>rr</sub>	-	25	-	ns
Reverse Recovery Charge	$V_{DS} = 450 \text{ V}, I_D = 100 \text{ A}$	Q <sub>rr</sub>	_	1709	_	μС
Peak Reverse Recovery Current	$V_{GS} = -5 \text{ V}/18 \text{ V}$ , $R_G = 1.8 \Omega$	I <sub>RRM</sub>		108		A
Peak Rate of Fall of Recovery Current		di/dt	_	13319	_	A/μs
Reverse Recovery Energy		E <sub>rr</sub>	_	875	_	μJ
Thermal Resistance - chip-to-case	M1, M2	R <sub>thJC</sub>	_	0.29	_	°C/W
Thermal Resistance - chip-to-heatsink	Thermal grease, Thickness = 2 Mil _2%, A = 2.8 W/mK	R <sub>thJH</sub>	-	0.46	-	°C/W

## **ELECTRICAL CHARACTERISTICS** (T<sub>.1</sub> = 25°C unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
THERMISTOR CHARACTERISTICS						
Nominal resistance	T = 25°C	R <sub>25</sub>	-	5	=	kΩ
Nominal resistance	T = 100°C	R <sub>100</sub>	-	457	=	Ω
Deviation of R25		ΔR/R	-3	-	3	%
Power dissipation		$P_{D}$	=	50	=	mW
Power dissipation constant			-	5	=	mW/K
B-value	B(25/50), tolerance ±3%		-	3375	_	K
B-value	B(25/100), tolerance ±3%		_	3455	-	K

## **ORDERING INFORMATION**

Orderable Part Number	Marking	Package	Shipping
NXH010P90MNF1PG	NXH010P90MNF1PG	F1-2PACK: Case 180BW Press-fit Pins (Pb – Free and Halide – Free)	28 Units / Blister Tray
NXH010P90MNF1PTG	NXH010P90MNF1PTG	F1-2PACK: Case 180BW Press-fit Pins with pre – applied thermal interface material (TIM) (Pb – Free and Halide – Free)	28 Units / Blister Tray

## **TYPICAL CHARACTERISTICS**

SiC MOSFET (M1/M2)

300

250

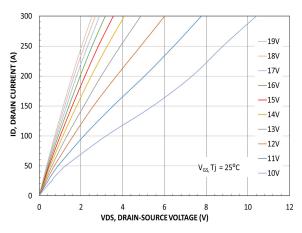
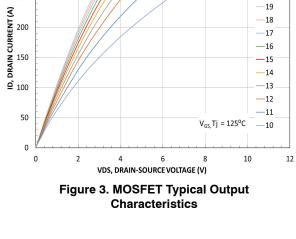


Figure 2. MOSFET Typical Output Characteristics



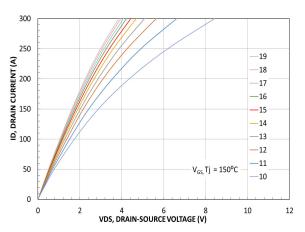


Figure 4. MOSFET Typical Output Characteristics

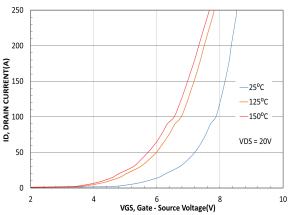


Figure 5. MOSFET Typical Transfer Characteristics

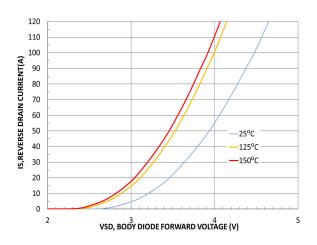


Figure 6. Body Diode Forward Characteristics

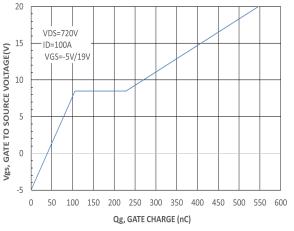


Figure 7. Gate-to-Source Voltage vs. Total Charge

## **TYPICAL CHARACTERISTICS**

SiC MOSFET (M1/M2)

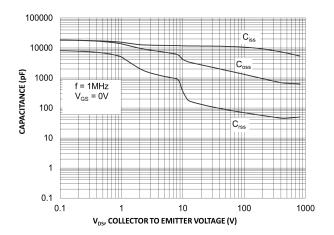


Figure 8. Capacitance vs. Drain-to-Source Voltage

## **TYPICAL CHARACTERISTICS**

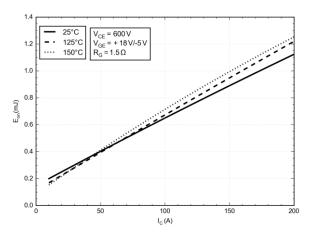


Figure 9. Typical Switching Loss Eon vs. IC

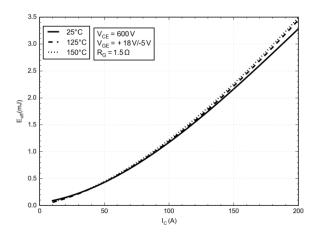


Figure 11. Typical Switching Loss Eoff vs. IC

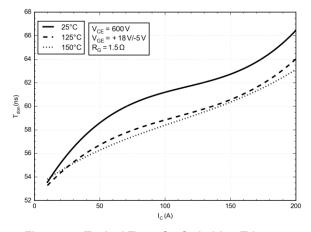


Figure 13. Typical Turn-On Switching Tdon vs. IC

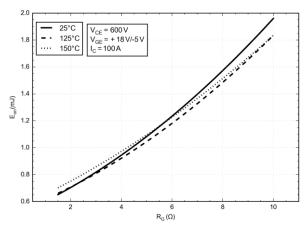


Figure 10. Typical Switching Loss Eon vs. R<sub>G</sub>

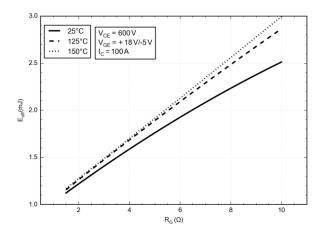


Figure 12. Typical Switching Loss Eoff vs. R<sub>G</sub>

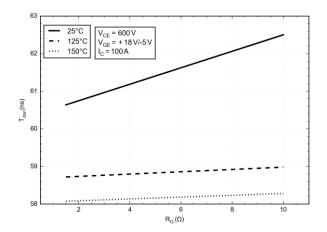


Figure 14. Typical Turn–On Switching Tdon vs.  $$R_{\mbox{\scriptsize G}}$$ 

## **TYPICAL CHARACTERISTICS**

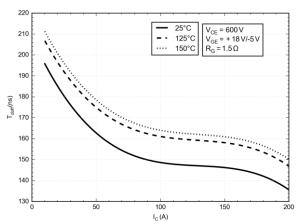


Figure 15. Typical Turn-off Switching Tdoff vs. IC

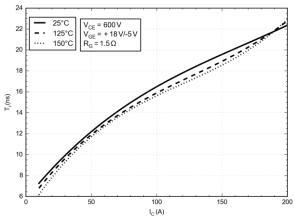


Figure 17. Typical Turn-On Switching Tr  $\,$  vs. IC

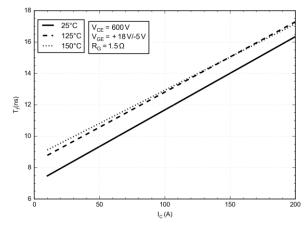


Figure 19. Typical Turn-Off Switching Tf  $\,$  vs. IC

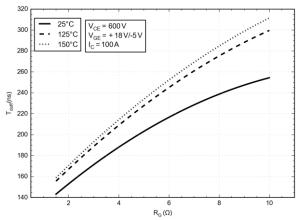


Figure 16. Typical Turn-off Switching Tdoff vs.  $$R_{\mbox{\scriptsize G}}$$ 

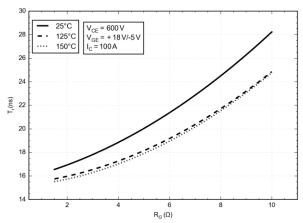


Figure 18. Typical Turn–On Switching Tr vs.  $\rm \textit{R}_{\rm G}$ 

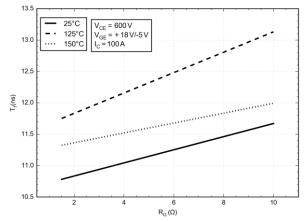


Figure 20. Typical Turn–Off Switching Tf vs.  $\rm R_{\rm G}$ 

## **TYPICAL CHARACTERISTICS**

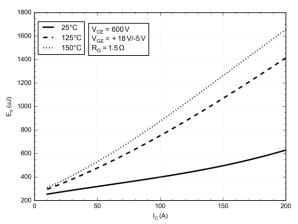


Figure 21. Typical Reverse Recovery Energy

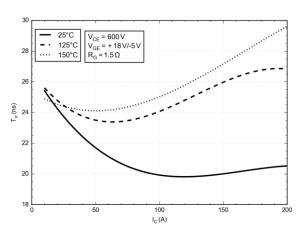


Figure 23. Typical Reverse Recovery Time vs.

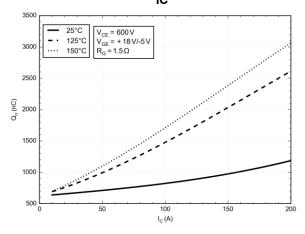


Figure 25. Typical Reverse Recovery Charge vs. IC

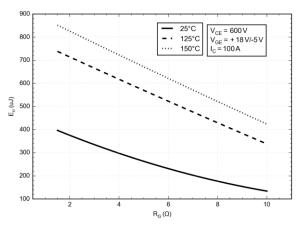


Figure 22. Typical Reverse Recovery Energy vs.  $R_{\mbox{\scriptsize G}}$ 

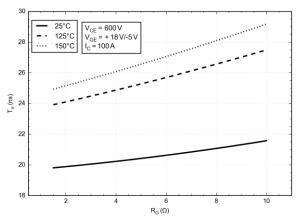


Figure 24. Typical Reverse Recovery Time vs.

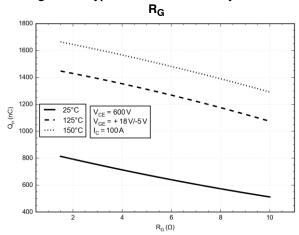


Figure 26. Typical Reverse Recovery Charge vs.  $R_{\mbox{\scriptsize G}}$ 

## **TYPICAL CHARACTERISTICS**

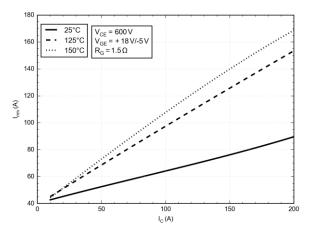


Figure 27. Typical Reverse Recovery Current vs. IC

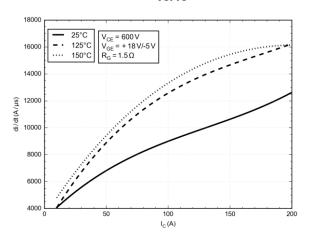


Figure 29. Typical di/dt vs. IC

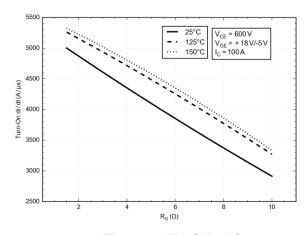


Figure 31. di/dt ON vs IC

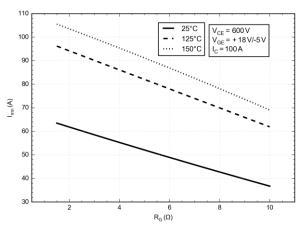


Figure 28. Typical Reverse Recovery Current vs.  $R_{\rm G}$ 

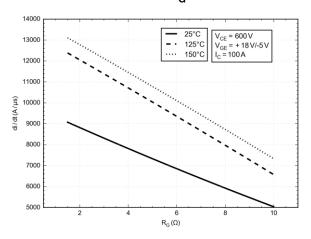


Figure 30. Typical di/dt vs. R<sub>G</sub>

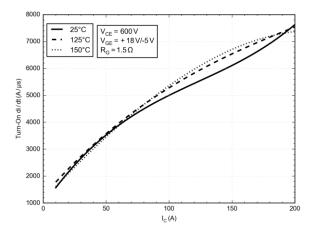


Figure 32. di/dt ON vs. R<sub>G</sub>

## **TYPICAL CHARACTERISTICS**

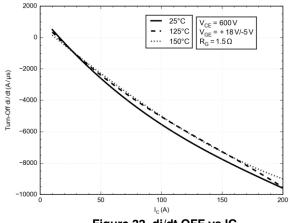
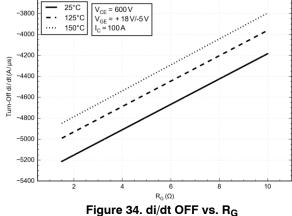


Figure 33. di/dt OFF vs IC



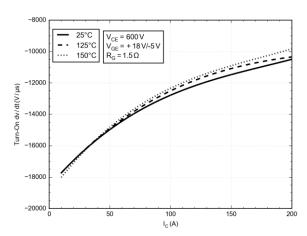


Figure 35. dv/dt ON vs IC

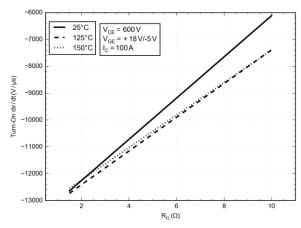


Figure 36. dv/dt ON vs. R<sub>G</sub>

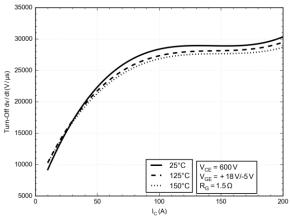


Figure 37. dv/dt OFF vs IC

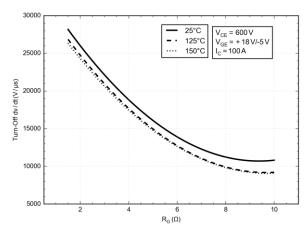


Figure 38. dv/dt OFF vs. R<sub>G</sub>

## TYPICAL CHARACTERISTICS

SiC MOSFET (M1/M2)

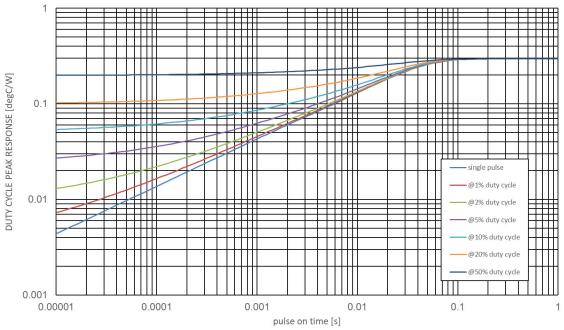


Figure 39. SiC Mosfet Junction-to-Case Transient Thermal Impedance

Table 1. FOSTER NETWORKS - M1, M2

Foster Element #	M1		M2	
	Rth (K/W)	Cth (Ws/K)	Rth (K/W)	Cth (Ws/K)
1	0.018018	0.006761	0.017423	0.006288
2	0.00725	0.110732	0.008856	0.083472
3	0.007012	0.219934	0.007085	0.218085
4	0.034121	0.121787	0.035241	0.119517
5	0.227927	0.132429	0.233897	0.129036

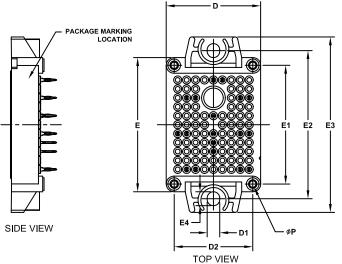
Table 2. CAUER NETWORKS - M1, M2

Cauer Element #	N	M1		M2	
	Rth (K/W)	Cth (Ws/K)	Rth (K/W)	Cth (Ws/K)	
1	0.025529	0.005642	0.026977	0.005357	
2	0.050904	0.03348	0.070046	0.034112	
3	0.066724	0.042125	0.094049	0.071939	
4	0.058571	0.063408	0.040991	0.068148	
5	0.092598	0.079724	0.064984	0.039596	



## PIM18 33.8x42.5 (PRESS FIT) CASE 180BW ISSUE B

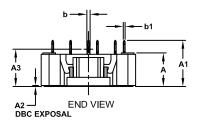
**DATE 30 APR 2021** 

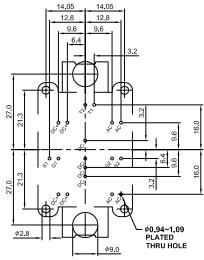


#### NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETERS
- 2. PIN POSITION TOLERANCE IS ± 0.4mm

	MILLIMETERS			
DIM	MIN.	NOM.	MAX.	
Α	11.65	12.00	12,35	
<b>A</b> 1	16.00	16.50	17.00	
A2	0.00	0.35	0.60	
A3	12.85	13.35	13.85	
b	1.15	1.20	1.25	
b1	0.59	0.64	0.69	
D	33.50	33.80	34.10	
D1	4.40	4.50	4.60	
D2	27.95	28.10	28.25	
E	47.70	48.00	48.30	
E1	42.35	42.50	42.65	
E2	52.90	53.00	53.10	
E3	62,30	62.80	63.30	
E4	4.90	5.00	5.10	
Р	2.20	2.30	2.40	





# GENERIC MARKING DIAGRAM\*

RECOMMENDED MOUNTING PATTERN

XXXXX = Specific Device Code AT = Assembly & Test Site Code

YYWW = Year and Work Week Code

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON19723H	Electronic versions are uncontrolled except when accessed directly from the Document Report Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	PIM18 33.8x42.5 (PRESS FIT)		PAGE 1 OF 1

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.